

Application/Control No.	Applicant(s)/Patent under Reexamination
10/710,693	BHOOSHAN ET AL.
Examiner	Art Unit
Phallaka Kik	2825

	SEARCHED				
Class	Subclass	Date	Examiner		
716	5,9,10	6/12/2006	PK		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
BRS (EAST)USPAT, USPGPUB CIs/Sub searched: 716/1-18 (see attached)	6/12/2006	PK
EPO, JPO, IBM TDB, Derwent (see attached)	6/12/2006	PK
IEE/IEEE Xplore (see attached)	6/12/2006	PK
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